

U.S. Department of Commerce, Patent and Trademark Office				Atty Docket No.	Serial No.			
				M-10696 US	09/742,029			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				Applicant(s), Gouheng, Zhao et al.				
				Filing Date	Group			
				December 20, 2000	2877			
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>JL</i>	AA	5,438,415	8/1/95	Kazama et al.				
<i>JP</i>	AB	5,793,480	8/11/98	Lacey et al.				
	AC	5,910,841	6/8/99	Masao				
<i>AS</i>	AD	6,134,011	10/17/00	Klein et al.				
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
Foreign Patent Documents							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AQ	International Search Report, 2002.						
	AR							
	AS							
Examiner <i>Zhou</i>		Date Considered <i>9/23/02</i>						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				Applicant(s)				
				GUOHENG ZHAO ET AL.				
				Filing Date	Group			
				December 20, 2000	2877			
U.S. Patent and Trademark Office								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>AS</i>	AA	5,517,312	5/14/96	Finarov	356	386	4/1/94	
	AB	5,607,800	3/4/97	Ziger	430	8	2/15/95	
	AC	5,739,909	4/14/98	Blayo et al.	356	369	10/10/95	
	AD	5,764,365	6/9/98	Finarov	356	381	5/13/96	
	AE	5,867,276	2/2/99	McNeil et al.	356	445	3/7/97	
	AF	5,963,329	10/5/99	Conrad et al.	356	372	10/31/97	
<i>AS</i>	AG	6,100,985	8/8/00	Scheiner et al.	356	381	3/12/99	
	AH							
	AI							
	AJ							
	AK							
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AQ	"Ultraviolet-visible ellipsometry for process control during the etching of submicrometer features," N. Blayo et al., <i>Journal of the Optical Society of America A</i> , Vol. 12, No. 3, March 1995, pp. 591-599						
	AR							
	AS							
Examiner <i>Guoheng Zhao</i>		Date Considered <i>9/23/02</i>						
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